

The eGaN<sup>®</sup> FET  
Journey Continues

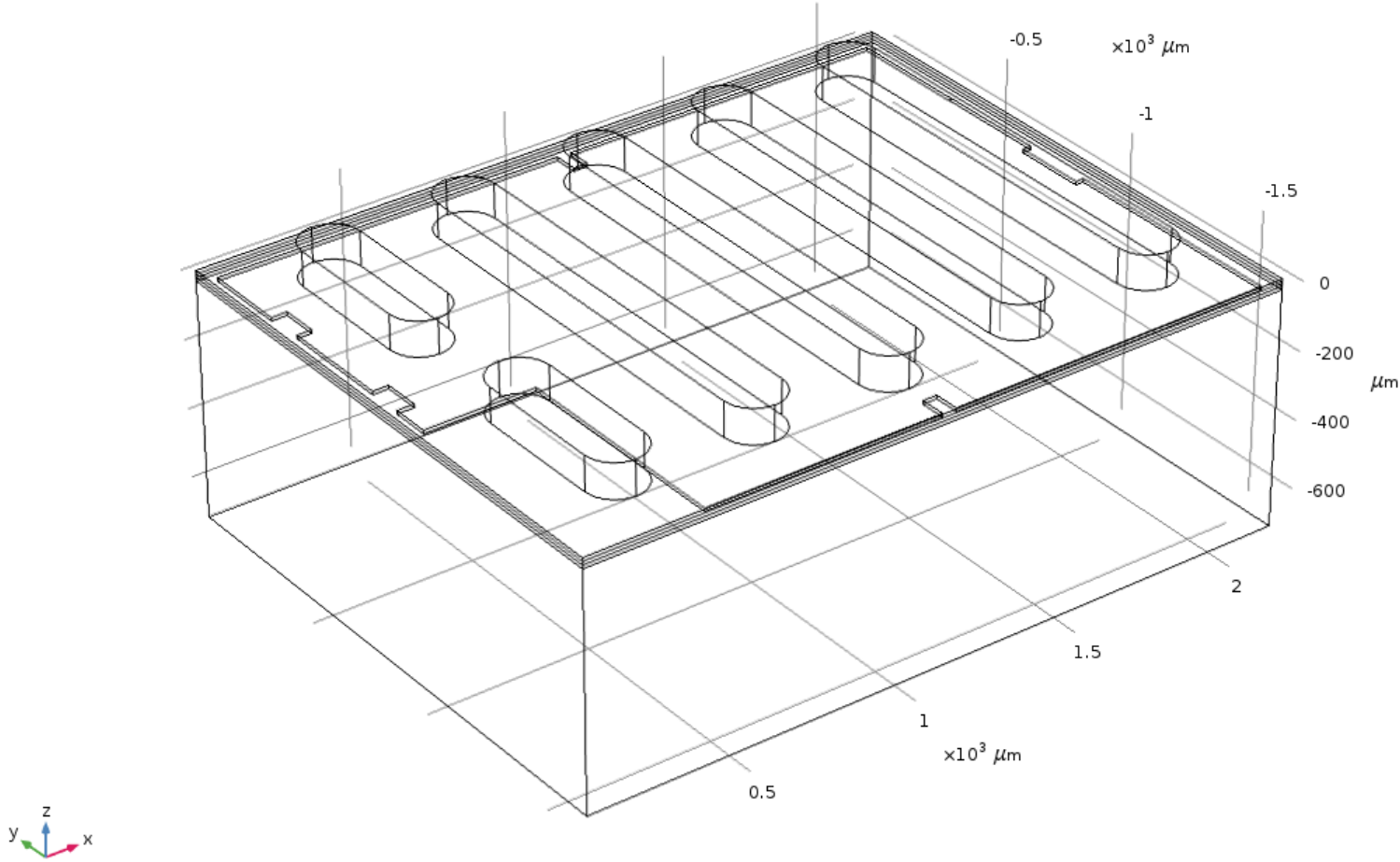


Thermal Model of EPC2016C

*Efficient Power Conversion Corporation*

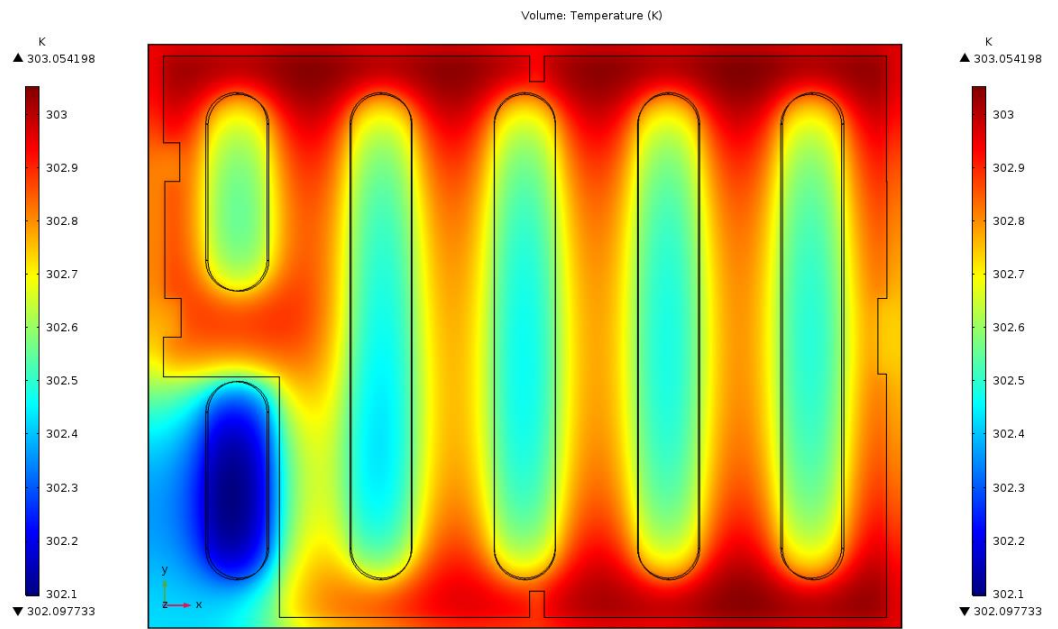
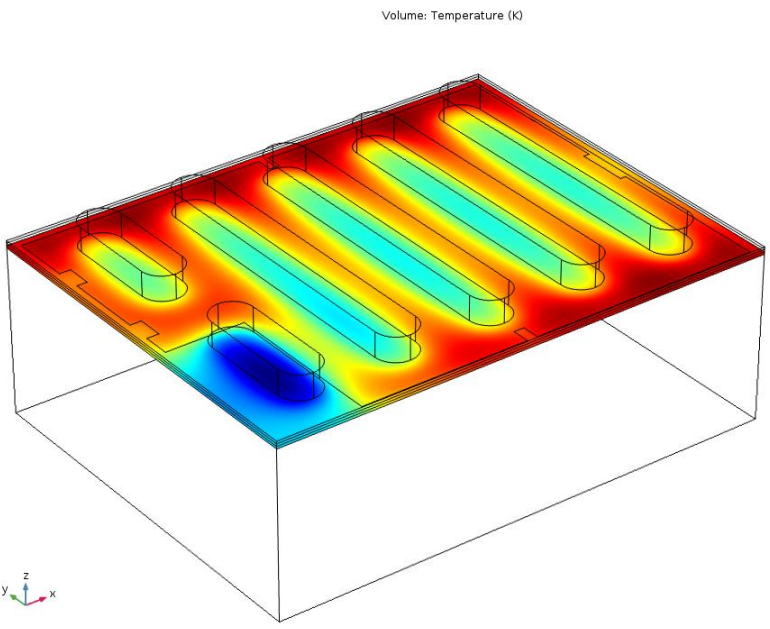
- The thermal model applies to EPC2016C.
- A power dissipation of 1 W in the device active area is assumed.
- Finite element analysis (FEA) thermal simulations
  - $R_{\Theta JB}$  and  $R_{\Theta JC}$  are obtained by stationary simulations.
  - $Z_{\Theta JB}$  and  $Z_{\Theta JC}$  are obtained by transient simulations.
- R-C thermal model is generated.

# EPC2016C device structure



# Steady-state $R_{\Theta JB}$

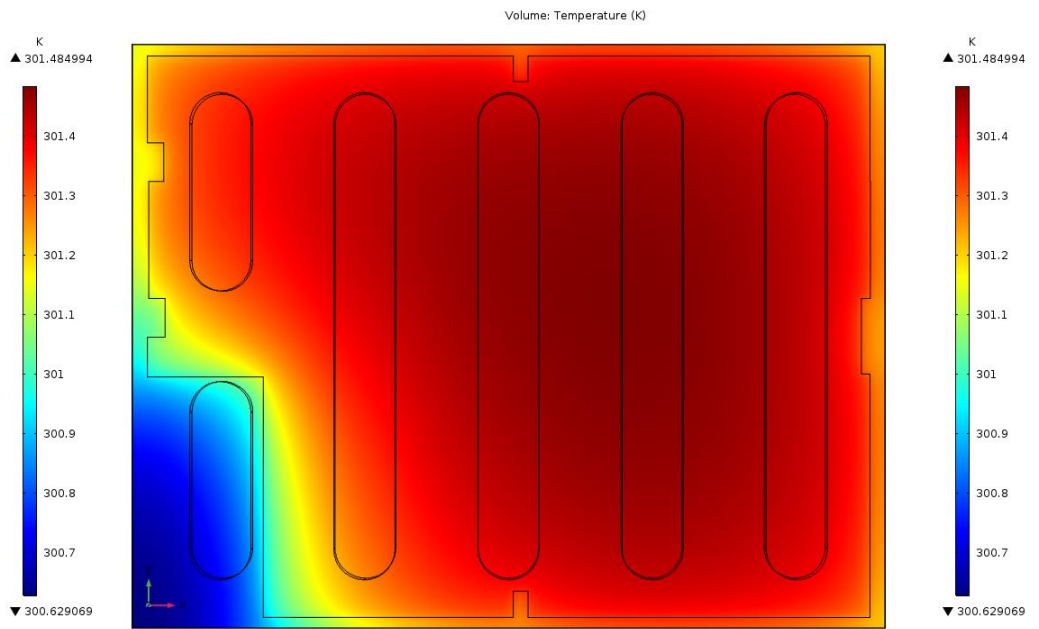
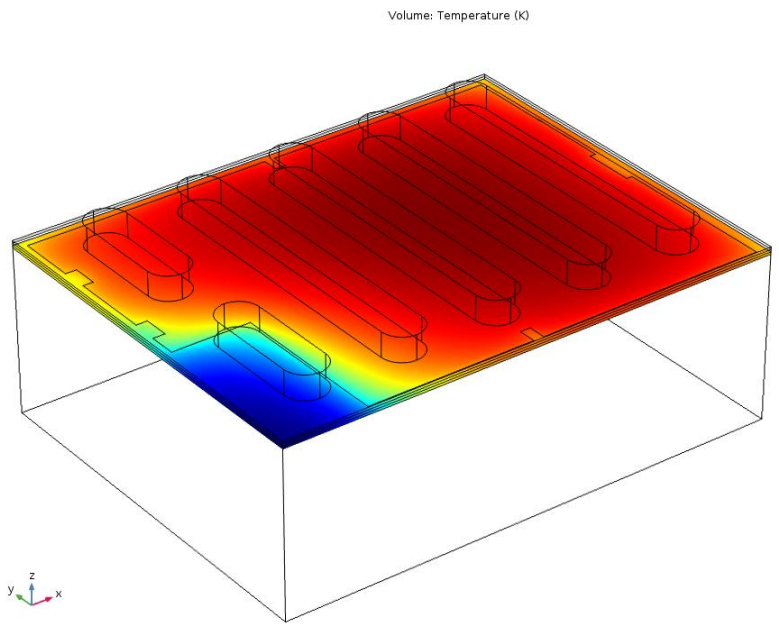
Typical  $R_{\Theta JB} = 3 \text{ }^\circ\text{C/W}$



- Operating condition: Power = 1 W in the active area.
- Boundary condition: Temperature of top of solder bars set to be 300 K.

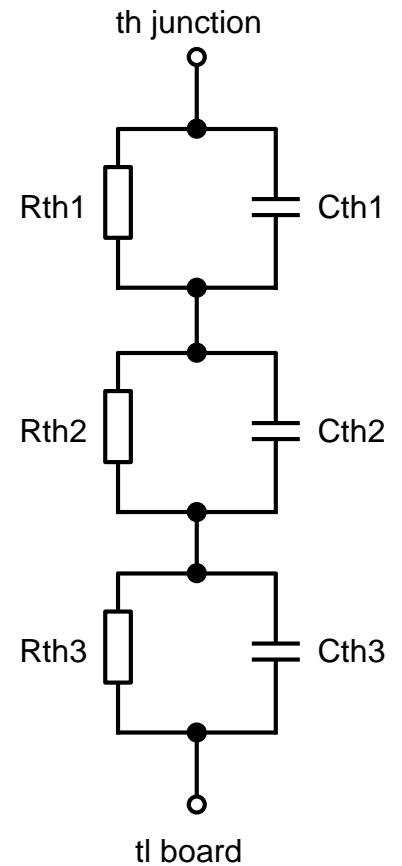
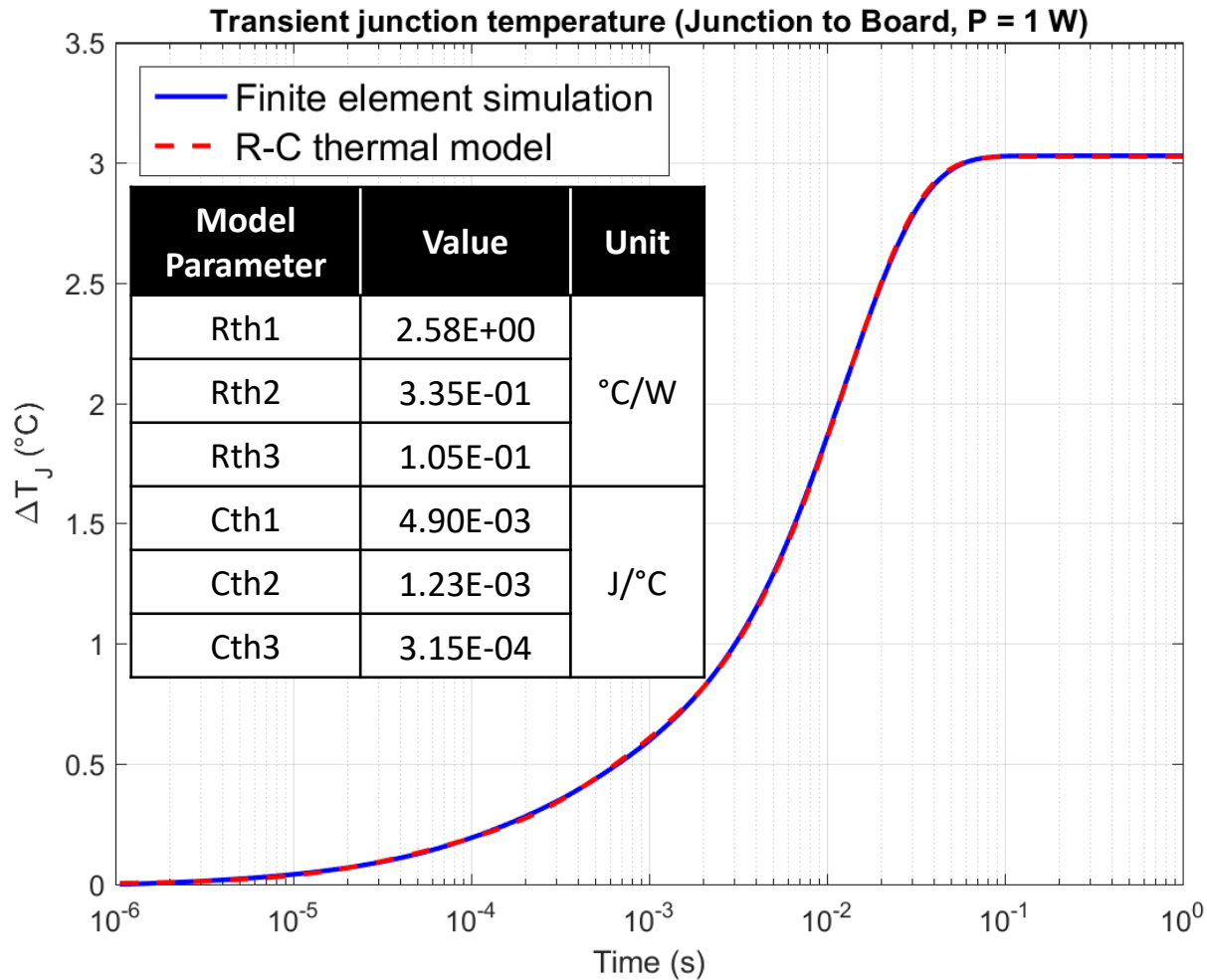
# Steady-state $R_{\Theta JC}$

Typical  $R_{\Theta JC} = 1.5 \text{ } ^\circ\text{C/W}$

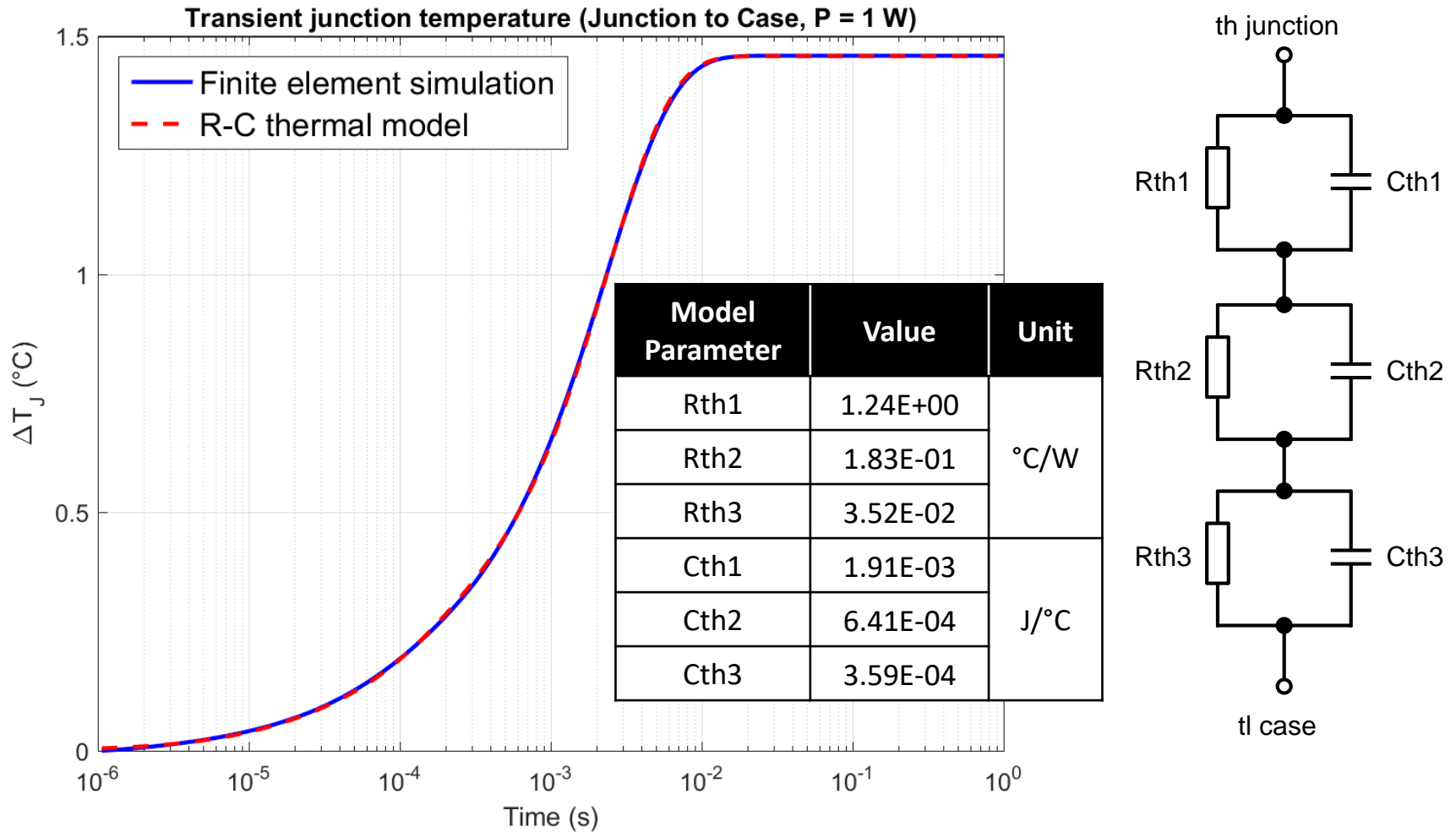


- Operating condition: Power = 1 W in the active area.
- Boundary condition: Temperature of bottom of the device backside set to be 300 K.

# $Z_{\Theta JB}$ R-C thermal model



# $Z_{\Theta JC}$ R-C thermal model





*The end of the  
road for silicon...*

*but a clear road  
ahead for GaN  
FETs and ICs!*